

Search Notes

Application/Control No.

10/016,434

Examiner

Annan Q. Shang

Applicant(s)/Patent under
Reexamination

TANIGAWA ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
725	37-61	2/8/2006	A.S

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR